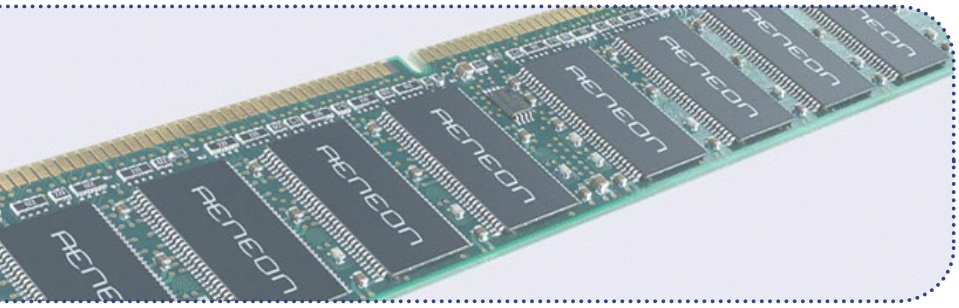

AENEON
Simply advanced

Unbuffered Memory Module
Data Sheet

AED760UD00-500

1 GByte DDR400 CL3 184-Pin UDIMM

Description

This data sheet describes features and specification of AENEON™ memory module family AED760UD00-500. The four digit product type postfix is for internal logistic purposes.

Features

- 1 GByte organized as 128 M × 64 bit
- Double Data Rate SDRAM components
- Speed grade DDR400 CL3 on component level
- Provides up to 3200 MByte per second on module level
- Module Code PC3200U–303312
- 184-Pin Dual Inline Memory Module (DIMM) with gold contacts
- Fitting in industry standard motherboards

Specification

Parameter	Values
Clock cycle time t_{CK} for CL3	5 ns (min.) / 8 ns (max.)
Clock cycle time t_{CK} for CL2.5	6 ns (min.) / 12 ns (max.)
Row cycle time t_{RC}	55 ns (min.)
Refresh row cycle time t_{RFC}	65 ns (min.)
Activate to read/write delay t_{RCD}	15 ns (min.)
Row active time t_{RAS}	40 ns (min.) / 70.000 ns (max.)
Single power supply $V_{DD} = V_{DDQ}$	2.6 V ± 0.1 V for t_{CK} < 6ns, else 2.5 V ± 0.2 V
Operating power I_{DD0}	3.7 W (max.)
Module dimensions L x W x H	133.35 mm x 30.0 mm x 4.0 mm (max.)
	5.25" x 1.18" x 0.16" (max.)

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   a. Have a detrimental effect on such Critical Systems in terms of reliability, effectiveness or safety; or
   b. Cause the failure of such Critical Systems; or
2. A failure or malfunction of such Critical Systems can reasonably be expected to –directly or indirectly–
   a. Endanger the health or the life of the user of such Critical Systems or any other person; or
   b. Otherwise cause material damages (including but not limited to damages or serious injury to life or property, whether tangible or intangible).